

Notice of References Cited

Application/Control No.

10/039,124

Applicant(s)/Patent Under

Reexamination

HOUSTON ET AL.

Examiner

Johannes P Mondt

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,104,061 ✓	08-2000	Forbes et al	257/330
	B	US-6,218,895 ✓	04-2001	De et al.	327/566
	C	US-6,018,172 ✓	01-2000	Hidaka et al.	257/296
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	S. Wolf, "Silicon Processing for the VLSI ERA", Volume 2 - Process Integration, Lattice Press, Sunset Beach, CA (USA), 1990 (ISBN 0-961672-4-5); pages 368-373. ✓
	V	A. Keshavarzi et al., "Technology Scaling Behavior of Optimum Reverse Body Bias for Standby Leakage Power Reduction in CMOS IC's", in Conference Proceedings of "Low Power Electronics and Design" 16-17 August 1999; pp. 252-254 (ISBN: 1-58113-133-X). ✓
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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